

Remarks on the thermally stimulated current measurement

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The measurement of thermally stimulated current was performed in the irradiated silicon pad detectors excited by light and by forward current. The TSC measurement was performed in the reverse bias regime. The differences in the spectrum are explained by a contribution of the non-equilibrium holes on the modulation of the microinhomogeneities related to the clusters and recombination in the case of light excitation.

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